
Prikaz lastnosti analizatorjev plina - 7. del: Analizatorji plina z nastavlјivim polprevodniškim laserjem (absorpcijska spektroskopija, ki uporablja nastavlјiv polprevodniški laser) (IEC 61207-7:2013)

Expression of performance of gas analyzers - Part 7: Tunable semiconductor laser gas analyzers (utilizing tunable semiconductor laser absorption spectroscopy)

Angabe zum Betriebsverhalten von Gasanalysatoren - Teil 7: Gasanalysatoren mit abstimmbaren Halbleiterlasern

Expression des performances des analyseurs de gaz - Partie 7: Analyseurs de gaz laser à semi-conducteurs accordables (à spectroscopie à absorption laser à semi-conducteur accordable)

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**Expression of performance of gas analyzers -
Part 7: Tuneable semiconductor laser gas analyzers
(IEC 61207-7:2013)**

Expression des performances
des analyseurs de gaz -
Partie 7: Analyseurs de gaz laser à semi-
conducteurs accordables
(CEI 61207-7:2013)

Angabe zum Betriebsverhalten
von Gasanalysatoren -
Teil 7: Gasanalysatoren mit abstimmbaren
Halbleiterlasern
(IEC 61207-7:2013)

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Foreword

The text of document 65B/876/FDIS, future edition 1 of IEC 61207-7, prepared by SC 65B "Measurement and control devices" of IEC/TC 65 "Industrial-process measurement, control and automation" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61207-7:2013.

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60654-1	1993	Industrial-process measurement and control equipment - Operating conditions - Part 1: Climatic conditions	EN 60654-1	1993
IEC 60654-2 + A1	1979 1992	Operating conditions for industrial-process measurement and control equipment - Part 2: Power	EN 60654-2 ¹⁾	1997
IEC 60654-3	1983	Operating conditions for industrial-process measurement and control equipment - Part 3: Mechanical influences	EN 60654-3	1997
IEC 60825-1	2007	Safety of laser products - Part 1: Equipment classification and requirements	EN 60825-1	2007
IEC 61207-1	2010	Expression of performance of gas analyzers - Part 1: General	EN 61207-1	2010

¹⁾ EN 60654-2 includes A1 to IEC 60654-2.

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NORME INTERNATIONALE



**Expression of performance of gas analyzers –
Part 7: Tuneable semiconductor laser gas analyzers**

**Expression des performances des analyseurs de gaz –
Partie 7: Analyseurs de gaz laser à semiconducteurs accordables**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

EXPRESSION OF PERFORMANCE OF GAS ANALYZERS –**Part 7: Tuneable semiconductor laser gas analyzers**

FOREWORD

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International Standard IEC 61207-7 has been prepared by subcommittee 65B: Measurement and control devices, of IEC technical committee 65: Industrial-process measurement, control and automation.

The text of this standard is based on the following documents:

FDIS	Report on voting
65B/876/FDIS	65B/891/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This International Standard is to be used in conjunction with IEC 61207-1:2010.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61207 series, under the general title *Expression of performance of gas analyzers*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

This part of IEC 61207 includes the terminology, definitions, statements and tests that are specific to tuneable semiconductor laser gas analyzers, which utilize tuneable semiconductor laser absorption spectroscopy (TSLAS).

Tuneable semiconductor laser gas analyzers utilize tuneable semiconductor lasers (e.g. diode lasers, quantum cascade lasers, interband cascade lasers) as light sources, whose wavelength covers ultraviolet, visible and infrared part of the electromagnetic spectrum, to detect the absorption spectra and thus determine the concentration of gases to be analyzed. These analyzers may employ different TSLAS techniques such as direct absorption spectroscopy, frequency modulation spectroscopy (FMS), wavelength modulation spectroscopy (WMS), etc. Multi-pass absorption spectroscopy, photoacoustic spectroscopy (PAS), and cavity-enhanced absorption spectroscopy (CEAS) such as cavity-ringdown spectroscopy (CRDS) are also used to take advantage of their high detection sensitivity.

Tuneable semiconductor laser gas analyzers are usually used to measure concentration of small molecule gases, such as oxygen, carbon monoxide, carbon dioxide, hydrogen sulfide, ammonia, hydrogen fluoride, hydrogen chloride, nitrogen dioxide, water vapour etc.

There are two main types of tuneable semiconductor laser gas analyzers: extractive and in situ analyzers. The extractive analyzers measure the sample gas withdrawn from a process or air by a sample handling system. The in situ analyzers measure the gas in its original place, including across-duct, probe and open-path types. Across-duct analyzers either have a laser source and a detector mounted on opposite sides of a duct, or both the laser and the detector are mounted on the same side and a retroreflector on the opposite side of a duct. Probe analyzers comprise a probe mounted into the duct, and the measured gas either passes through or diffuses into the measuring optical path inside the probe. And open-path analyzers measure the gas in an open environment with a hardware approach similar to across duct analyzers (source and detector on opposite sides of the open area or a retroreflector on one side and the source and detector on the opposite side), except the sample is in an open path and not contained in a duct.

NOTE 1 Traditionally, only diode lasers were employed, and thus tuneable diode laser gas analyzers and tuneable diode laser absorption spectroscopy (TDLAS) are widely used terms. However, with the development of laser technology, many other types of semiconductor lasers, such as quantum cascade lasers (QCLs) and interband cascade lasers (ICLs) have been developed and employed in laser gas analyzers. Therefore, the term of semiconductor laser rather than diode laser is used in this standard to reflect this technology advancement.

NOTE 2 Though tuneable semiconductor laser photoacoustic spectroscopy (PAS) is in principle different from absorption spectroscopy typically used in tuneable semiconductor laser gas analyzers, the hardware and data reduction software are almost the same for analyzers utilizing these two spectroscopy technologies, and thus PAS is considered a variant of absorption spectroscopy and this standard also applies to the analyzers based on PAS.